

Notice of References Cited		Application/Control No. 10/630,223	Applicant(s)/Patent Under Reexamination MICHON ET AL.	
		Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,027,733	02-2000	Wang et al.	424/243.1
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	Wessels et al. PNAS 84: 9170-9174, 1987		
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.